

<b>Notice of References Cited</b>	Application/Control No. 10/802,184	Applicant(s)/Patent Under Reexamination YOSHII ET AL.	
	Examiner James A: Dudek	Art Unit 2871	Page 1 of 1

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*	B	US-2005/0094068	05-2005	Ikeno et al.	349/114
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	M	US-			

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**NON-PATENT DOCUMENTS**

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